

John Fredric Schneider

Argonne National Laboratory
Chemical Sciences and Engineering Division
9700 South Cass Avenue, Building 200
Argonne, IL 60439-4837
phone: 630/252-8923, fax: 630/252-4886
e-mail: jschneider@anl.gov

Professional Experience

- **1980-Present.** Argonne National Laboratory (ANL)
 - **1990-Present.** Started as a Scientist and promoted to Group Leader of the Chemical Analysis and Research Group.
 - **1988-1990.** Associate Group Leader in the Analytical Chemistry Laboratory.
 - **1987.** Scientist in the Analytical Chemistry Laboratory.
 - **1984-1987.** Scientific Associate in the Analytical Chemistry Laboratory.
 - **1980-1984.** Scientific Assistant in the Analytical Chemistry Laboratory.
- **2006-Present.** Research Assistant Professor at the Illinois Institute of Technology in Chicago, Illinois.
- **1993-1997.** Part-time Chemistry Instructor at Trinity Christian College in Palos Heights, Illinois.
- **1980-1993.** Part-time Chemistry Instructor at College of DuPage in Glen Ellyn, Illinois.
- **1978-1980.** Development Chemist at Diamond Shamrock Chemical Company.

Education

- M.S., Analytical Chemistry, Northern Illinois University
- B.S., Chemistry, Elmhurst College

Technical Specialties

- Electronic nose development (chemical sensor array)
- Chemical warfare agent analysis
- Explosives analysis
- Environmental sampling and analysis
- Field analytical chemistry
- X-ray Fluorescence analysis for metals in the field
- Environmental chemistry
- Gas chromatography (GC)
- GC/IR
- GC/MS
- GC/MSD
- Matrix Isolation FTIR

- Priority pollutant determination by EPA CLP methods
- Organic analysis
- Vitamin analysis
- HPLC
- NMR
- UV-visible spectroscopy
- Wet analysis
- Process development from lab scale to pilot plant

Professional Society Affiliations

- Board Member of the On-Site 2009 Conference on On-Site Analysis and Homeland Security
- Member of The American Chemical Society
- Member of The Chicago Chromatography Discussion Group

Publications

- Presentations: 4
- Journal Articles and Technical Reports: 45